

**Notice of References Cited**Application/Control No.  
09/475,487Applicant(s)/Patent Under  
Reexamination  
ASSADI, AZARExaminer  
Paul W MyersArt Unit  
2612

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,501,065 B1	12-2002	Uppal et al.	250/214.1
	B	US-5,600,486 A	02-1997	Gal et al.	359/569
	C	US-5,056,894	10-1991	Kuijk et al.	349/50
	D	US-6,353,228 B1	03-2002	Itabashi, Satoshi	250/370.11
	E	US-5,408,343 A	04-1995	Sugiura et al.	358/520
	F	US-6,163,386 A	12-2000	Kobayashi et al.	358/482
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Dictionary onlook.com definition: indium tin oxide
	V	Dictionary onlook.com definiton: silica□□
	W	Encyclopedia: Wikipedia definiton and use of silica
	X	Low-temperature sol-gel process developed, November 1997, SPIE Web, OP Reports

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.